

# Risk bounds for regression and classification with structured feature maps

Andrew D. McRae

Georgia Tech School of Electrical and Computer Engineering

[admcræ@gatech.edu](mailto:admcræ@gatech.edu)

Joint work with Vidya Muthukumar, Justin Romberg, and Mark Davenport

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## Setup: feature maps for linear regression

Linear regression model with feature map  $\boldsymbol{\phi}(x) = (\phi_1(x), \dots, \phi_d(x))$ :

$$f(x, \mathbf{w}) = \langle \boldsymbol{\phi}(x), \mathbf{w} \rangle = \sum_{\ell} w_{\ell} \phi_{\ell}(x)$$

Suppose  $f^*(x) = f(x, \mathbf{w}^*)$ , and observe  $y_i = f^*(x_i) + \xi_i$  for  $i = 1, \dots, n$ . In matrix form,

$$\underbrace{\begin{bmatrix} y_1 \\ \vdots \\ y_n \end{bmatrix}}_{\mathbf{y}} = \underbrace{\begin{bmatrix} \phi_1(x_1) & \cdots & \phi_d(x_1) \\ \vdots & \ddots & \vdots \\ \phi_1(x_n) & \cdots & \phi_d(x_n) \end{bmatrix}}_{\boldsymbol{\Phi}} \mathbf{w}^* + \underbrace{\begin{bmatrix} \xi_1 \\ \vdots \\ \xi_n \end{bmatrix}}_{\boldsymbol{\xi}}$$

Standard ridge regression estimate with regularization  $\delta \geq 0$ :

$$\hat{\mathbf{w}} = (\delta \mathbf{I}_d + \boldsymbol{\Phi}^T \boldsymbol{\Phi})^{-1} \boldsymbol{\Phi}^T \mathbf{y} = \boldsymbol{\Phi}^T (\delta \mathbf{I}_n + \underbrace{\boldsymbol{\Phi} \boldsymbol{\Phi}^T}_{\text{Gram matrix}})^{-1} \mathbf{y}$$

## Noise requires regularization—right?

$$\mathbf{y} = \underbrace{\Phi}_{n \times d} \mathbf{w}^* + \boldsymbol{\xi}$$

$$\hat{\mathbf{w}} = \Phi^T (\delta I_n + \Phi \Phi^T)^{-1} (\Phi \mathbf{w}^* + \boldsymbol{\xi})$$

If  $\delta = 0$  and  $d \geq n$ ,  $f(\cdot, \hat{\mathbf{w}})$  will **interpolate** the samples

$$\Phi \hat{\mathbf{w}} = \Phi \Phi^T (\Phi \Phi^T)^{-1} \mathbf{y} = \mathbf{y}$$

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## Overparametrization...



Lots of recent papers show that in certain settings, interpolating noise isn't too bad

► Why?

Split the features into two groups:

$$\boldsymbol{\phi}(x) = (\underbrace{\phi_1(x), \dots, \phi_p(x)}_{\boldsymbol{\phi}_H(x)}, \underbrace{\phi_{p+1}(x), \dots, \phi_d(x)}_{\boldsymbol{\phi}_R(x)}), \quad \boldsymbol{\Phi} = \begin{bmatrix} \underbrace{\boldsymbol{\Phi}_H}_{n \times p} & \underbrace{\boldsymbol{\Phi}_R}_{n \times (d-p)} \end{bmatrix}$$

Then

$$\boldsymbol{\Phi}\boldsymbol{\Phi}^T = \boldsymbol{\Phi}_H\boldsymbol{\Phi}_H^T + \boldsymbol{\Phi}_R\boldsymbol{\Phi}_R^T$$

## ...can give implicit regularization

Gram matrix:  $\Phi\Phi^T = \Phi_H\Phi_H^T + \Phi_R\Phi_R^T$

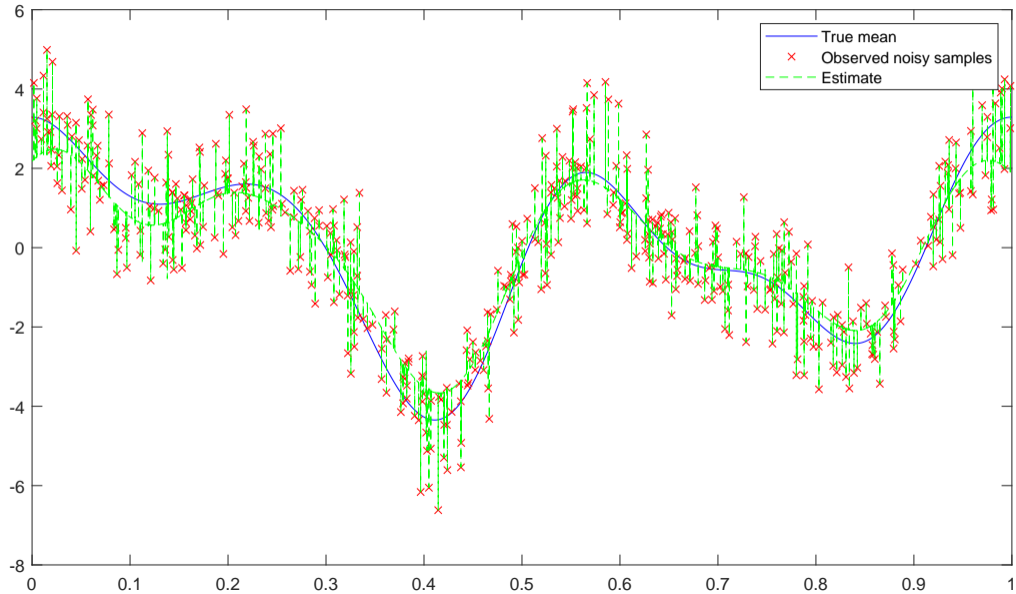
- ▶ If  $d - p \gg n$ , sometimes  $\Phi_R\Phi_R^T \approx rI_n$  (for some  $r > 0$ )! So  $\hat{w} \approx \Phi^T(rI_n + \Phi_H\Phi_H^T)^{-1}y$ .
- ▶ Previous work<sup>1,2</sup> assumes **independent features**
  - ▶ Only requires  $d - p \gtrsim n$
  - ▶ Not always realistic: kernel/RKHS regression, Fourier features, etc.
- ▶ Our work: for merely **uncorrelated** features,  $d - p \gtrsim n^2$  is enough

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<sup>1</sup>Peter L. Bartlett et al. (2020). "Benign overfitting in linear regression". In: *Proc. Natl. Acad. Sci. U.S.A.* 117.48, pp. 30063–30070.

<sup>2</sup>Tengyuan Liang and Alexander Rakhlin (2020). "Just interpolate: Kernel "Ridgeless" regression can generalize". In: *Ann. Stat.* 48.3, pp. 1329–1347.

## Example (Fourier series)



## What about classification?

- ▶ Now  $y$  is a label in  $\{-1, 1\}$ . Let

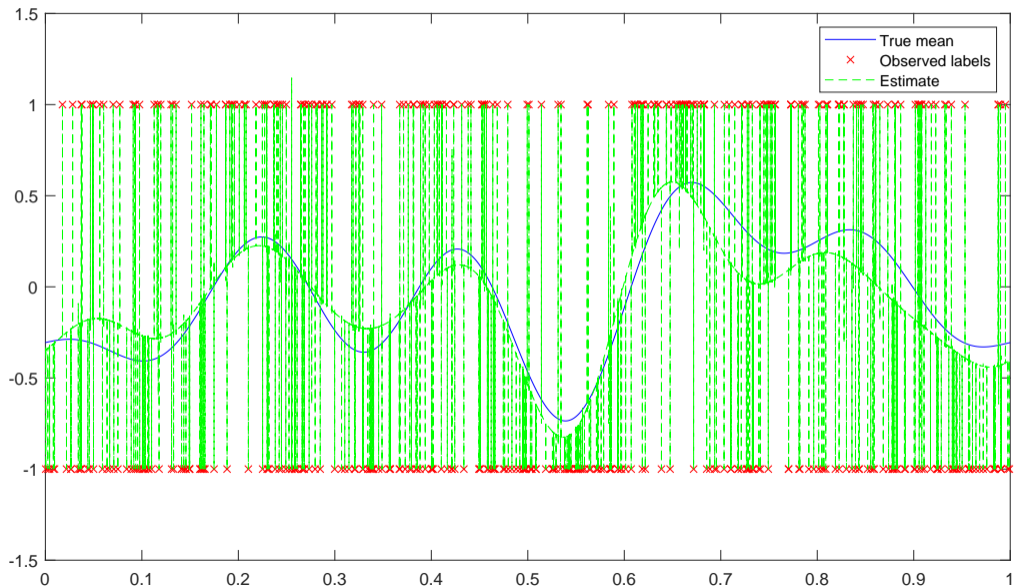
$$f^*(x) = \mathbf{E}[y | x] = 2 \mathbf{P}[y = 1 | x] - 1, \quad \xi = y - f^*(x)$$

- ▶ Classifier: estimate  $\hat{\mathbf{w}}$  as before from samples  $(x_1, y_1), \dots, (x_n, y_n)$  and set

$$\hat{y}(x) = \text{sign}(f(x, \hat{\mathbf{w}}))$$



# Binary labels example



## Finer analysis for classification

$$\hat{y}(x) = \text{sign}(f(x, \hat{\mathbf{w}}))$$

- ▶ Classification is **easier** than regression since we only need the sign!
  - ▶  $\exists$  regimes where regression error is large but classification risk is small
  - ▶ Previously shown under very special conditions<sup>3</sup>
  - ▶ We've proved this in more general setting (uncorrelated features, more general  $f^*$ )
  - ▶ Basic idea: if  $f(x, \hat{\mathbf{w}}) = af^*(x) + h(x)$ , then (excess) classification risk is small as long as  $a > 0$  and  $\|h\|_{L_1} \ll a$ , even if  $a \ll 1$ !

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<sup>3</sup>Vidya Muthukumar et al. (2021). "Classification vs. regression in overparameterized regimes: Does the loss function matter?" In: *J. Mach. Learn. Res.* arXiv: 2005.08054. Forthcoming.

## Large regression but small classification error

